Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/510,013	SHIN ET AL.
Examiner	Art Unit

Tai Duong

2871

SEARCHED						
Cla	ass	Subclass	Date		Examiner	
34	49	38	3/17/2007		TD	
-		43				
		48				
		128				
		129				
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		167				
		177				
		187				
2	57	59				
		72				
4:	38	30				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
03/17	ext search, /2007, ence printout	3/17/2007	TD		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST (US PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM TDB) see search history printout	3/17/2007	TD			